

400V, N-CHANNEL

REF: MIL-PRF-19500/557



REPETITIVE AVALANCHE AND dv/dt RATED HEXFET® TRANSISTORS THRU-HOLE TO-205AF (TO-39)

Product Summary

| Part Number | BVDSS | RDS(on) | I _D |
|-------------|-------|---------|----------------|
| IRFF330 | 400V | 1.0Ω | 3.0A |



Description

The HEXFET® technology is the key to International Rectifier's HiRel advanced line of power MOSFET transistors. The efficient geometry and unique processing of this latest "State of the Art" design achieves: very low on state resistance combined with high trans conductance.

The HEXFET transistors also feature all of the well established advantages of MOSFETs such as voltage control, very fast switching and temperature stability of the electrical parameters.

They are well suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers and high energy pulse circuits.

Features

- Repetitive Avalanche Ratings
- · Dynamic dv/dt Rating
- · Hermetically Sealed
- Simple Drive Requirements
- ESD Rating: Class 1C per MIL-STD-750, Method 1020

Absolute Maximum Ratings

| Symbol | Parameter | Value | Units |
|---|---------------------------------|---|-------|
| I_{D1} @ V_{GS} = 10V, T_{C} = 25°C | Continuous Drain Current | 3.0 | |
| I _{D2} @ V _{GS} = 10V, T _C = 100°C | Continuous Drain Current | 2.0 | Α |
| I _{DM} @ T _C = 25°C | Pulsed Drain Current ① | 12 | |
| P _D @ T _C = 25°C | Maximum Power Dissipation | 25 | W |
| | Linear Derating Factor | 0.20 | W/°C |
| V_{GS} | Gate-to-Source Voltage | ± 20 | V |
| E _{AS} | Single Pulse Avalanche Energy ② | 191 | mJ |
| I _{AR} | Avalanche Current ① | 3.0 | Α |
| E _{AR} | Repetitive Avalanche Energy ① | 2.5 | mJ |
| dv/dt | Peak Diode Recovery dv/dt ③ | 4.0 | V/ns |
| T _J | Operating Junction and | -55 to + 150 | |
| T _{STG} | Storage Temperature Range | -55 10 + 150 | °C |
| | Lead Temperature | 300 (0.063 in. /1.6 mm from case for 10s) | |
| | Weight | 0.98 (Typical) | g |

For Footnotes, refer to the page 2.



Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

| Symbol | Parameter | Min. | Тур. | Max. | Units | Test Conditions |
|--------------------------------|--------------------------------------|------|------|-------|-------|--|
| BV _{DSS} | Drain-to-Source Breakdown Voltage | 400 | | | V | $V_{GS} = 0V, I_D = 1.0mA$ |
| $\Delta BV_{DSS}/\Delta T_{J}$ | Breakdown Voltage Temp. Coefficient | | 0.37 | | V/°C | Reference to 25°C, I _D = 1.0mA |
| | Otatia Basia ta Osama On Basiatana | | | 1.0 | 0 | V _{GS} = 10V, I _{D2} = 2.0A ④ |
| R _{DS(on)} | Static Drain-to-Source On-Resistance | | | 1.10 | Ω | V _{GS} = 10V, I _{D1} = 3.0A ④ |
| $V_{GS(th)}$ | Gate Threshold Voltage | 2.0 | | 4.0 | V | $V_{DS} = V_{GS}, I_{D} = 250 \mu A$ |
| Gfs | Forward Transconductance | 2.0 | | | S | V _{DS} = 15V, I _{D2} = 2.0A ④ |
| I_{DSS} | Zara Cata Valtaria Drain Current | | | 25 | | V _{DS} =320 V, V _{GS} = 0V |
| | Zero Gate Voltage Drain Current | | | 250 | μΑ | $V_{DS} = 320V, V_{GS} = 0V, T_{J} = 125^{\circ}C$ |
| I_{GSS} | Gate-to-Source Leakage Forward | | | 100 | nA | V _{GS} = 20V |
| | Gate-to-Source Leakage Reverse | | | -100 | П | V _{GS} = -20V |
| Q_G | Total Gate Charge | 19.1 | | 34.75 | | $I_{D1} = 3.0A$ |
| Q_{GS} | Gate-to-Source Charge | 1.0 | | 5.75 | nC | V _{DS} = 200V |
| Q_{GD} | Gate-to-Drain ('Miller') Charge | 6.7 | | 16.59 | | V _{GS} = 10V |
| $t_{d(on)}$ | Turn-On Delay Time | | | 30 | | V _{DD} = 200V |
| tr | Rise Time | | | 35 | 20 | $I_{D1} = 3.0A$ |
| $t_{d(off)}$ | Turn-Off Delay Time | | | 55 | ns | $R_G = 7.5\Omega$ |
| t_f | Fall Time | | | 35 | | V _{GS} = 10V |
| Ls +L _D | Total Inductance | | 7.0 | | nH | Measured from Drain lead (6mm / 0.25 in from package) to Source lead (6mm/ 0.25 in from package) with Source wire internally bonded from Source pin to Drain pin |
| C _{iss} | Input Capacitance | | 620 | | | V _{GS} = 0V |
| C _{oss} | Output Capacitance | | 200 | | pF | V _{DS} = 25V |
| C _{rss} | Reverse Transfer Capacitance | | 75 | | | f = 1.0 MHz |

Source-Drain Diode Ratings and Characteristics

| Symbol | Parameter | Min. | Тур. | Max. | Units | Test Conditions |
|-----------------|--|--|------|------|-------|---|
| Is | Continuous Source Current (Body Diode) | | | 3.0 | ^ | |
| I _{SM} | Pulsed Source Current (Body Diode) ① | | | 12 | A | |
| V_{SD} | Diode Forward Voltage | | | 1.4 | V | $T_J = 25^{\circ}C, I_S = 3.0A, V_{GS} = 0V$ |
| t _{rr} | Reverse Recovery Time | | | 700 | ns | $T_J = 25^{\circ}C, I_F = 3.0A, V_{DD} \le 50V$ |
| Q _{rr} | Reverse Recovery Charge | | | 6.2 | μC | di/dt = 100A/μs ④ |
| t _{on} | Forward Turn-On Time | Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D) | | | | |

Thermal Resistance

| Symbol | Parameter | Min. | Тур. | Max. | Units |
|-----------------|--|------|------|------|-------|
| $R_{	heta JC}$ | Junction-to-Case | | | 5.0 | °CAM |
| $R_{\theta JA}$ | Junction-to-Ambient (Typical Socket Mount) | | | 175 | °C/W |

Footnotes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- \odot V_{DD} = 50V, starting T_J = 25°C, L = 42.5mH, Peak I_L = 3.0A, V_{GS} = 10V, R_G = 25 Ω
- $\ \Im$ $\ I_{SD} \leq 3.0 A, \ di/dt \leq 90 A/\mu s, \ V_{DD} \leq 400 V, \ T_{J} \leq 150 ^{\circ} C, \ Suggested \ R_{G}$ = 7.5 Ω
- 4 Pulse width $\leq 300 \ \mu s$; Duty Cycle $\leq 2\%$

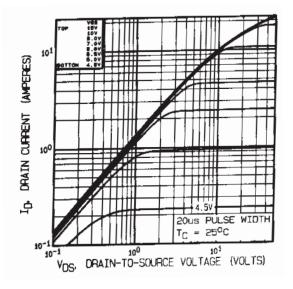


Fig 1. Typical Output Characteristics

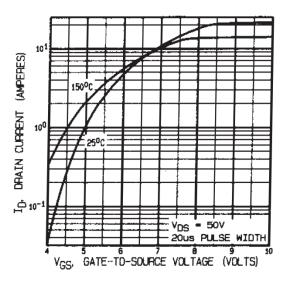


Fig 3. Typical Transfer Characteristics

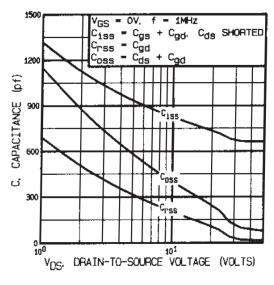


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

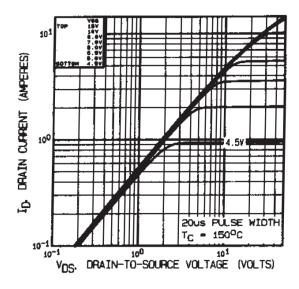


Fig 2. Typical Output Characteristics

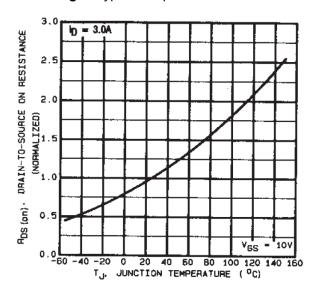


Fig 4. Normalized On-Resistance Vs. Temperature

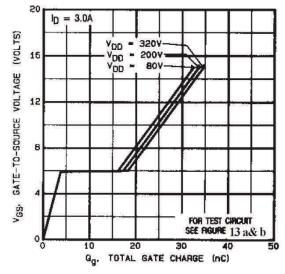


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

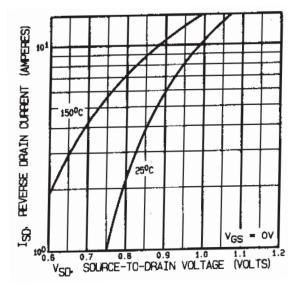


Fig 7. Typical Source-Drain Diode Forward Voltage

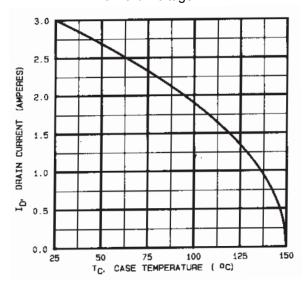


Fig 9. Maximum Drain Current Vs. Case Temperature

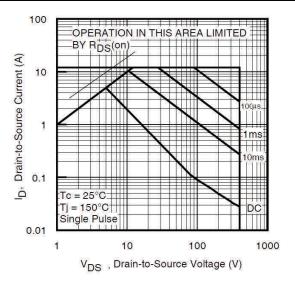


Fig 8. Maximum Safe Operating Area

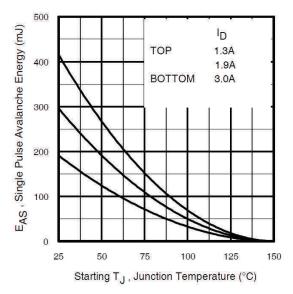


Fig 10. Maximum Avalanche Energy Vs. Drain Current

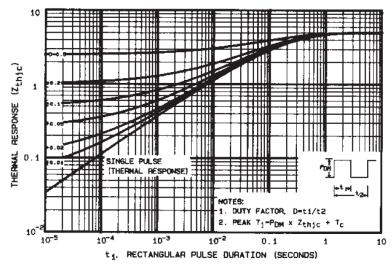


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

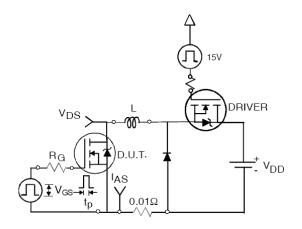


Fig 12a. Unclamped Inductive Test Circuit

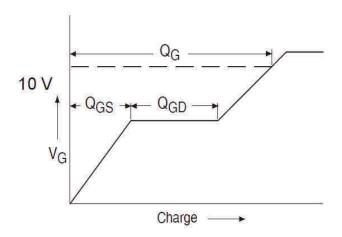


Fig 13a. Gate Charge Waveform

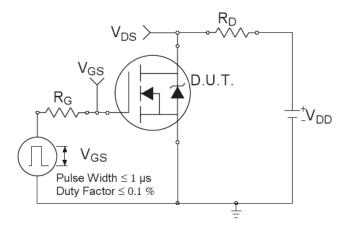


Fig 14a. Switching Time Test Circuit

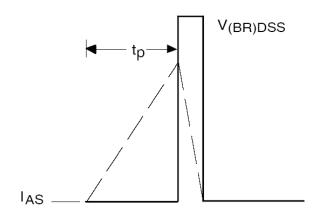


Fig 12b. Unclamped Inductive Waveforms

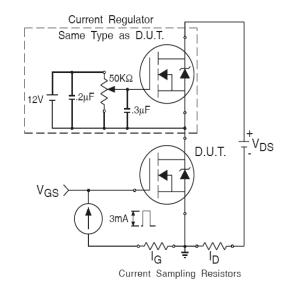


Fig 13b. Gate Charge Test Circuit

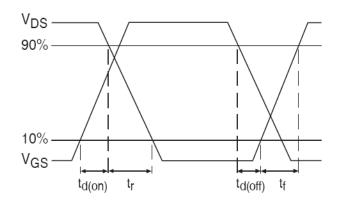
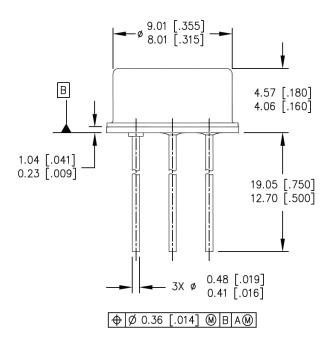


Fig 14b. Switching Time Waveforms



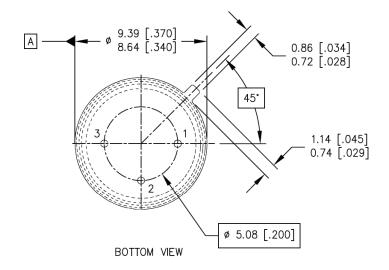
Case Outline and Dimensions - TO-205AF (TO-39)



NOTES: SIDE VIEW

1. DIMENSIONING AND TOLERANCING PER ASME 14.5M-1994.

- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. CONTROLLING DIMENSION: INCH.
- 4. CONFORMS TO JEDEC OUTLINE TO-205AF (TO-39).



LEGEND

1- SOURCE

2- GATE

3- DRAIN (CONNECTED TO THE CASE)



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